IAP12 Rec'd PCT/PTO 29 NOV 2005

MODIFIED PTO/SB/08 A & B (06-03)

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Substitute for Form 1449 A & B/PTO			v	Complete if Kn wo / 55836/		
		•		Application Number	Not Yet Assigned	
INFORMATION DISCLOSURE				Confirmation Number	Not Yet Assigned	
STATEMENT BY APPLICANT				Filing Date	November 29, 2005	
<u>DITT DI</u>	<u> </u>		<u> </u>	First Named Inventor	Munehiro TADA	
(use as many sheets as necessary)				Art Unit	Not Yet Assigned	
(,		,	Examiner Name	Not Yet Assigned	
Sheet	1	of	1	Attorney Docket Number	Q91732	

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		Document Nu	ımber				
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Initials*	No.1	Country Code ³	Number ⁴	Kind Code ⁵ (if known)		Applicant of Cited Document	Translation
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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
		Tada, M., et al. "BARRIER-METAL-FREE (BMF), Cu DUAL-DAMASCENE INTERCONNECTS WITH Cu-epi-CONTACTS BURIED IN ANTI-DIFFUSIVE, LOW-k ORGANIC FILM," 2001 Symposium on VLSI Technology, June 12, 2001, pages 13-14.	
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Examiner Signature	Date Considered
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